TL2000

Opto-electronics Chip Tester





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ficonTEC's series of testing machines is focused on automated electro-optical characterization of semiconductor chips. The ficonTEC TL2000 is a fully automated test and inspection system for unmounted laser diode bars, single chips and chips on submounts.

The system can be configured to perform measurements on the complete bar at once or on each individual emitter of the bar. Typical measurements are LIV tests, spectral characterization, and examination of the far field distribution.



Vacuum Chuck

The temperature controlled vacuum chuck is the element responsible for reliable fixture of the device under test (DUT) and temperature control.

- Changeable chuck allows various DUT designs
- Temperature range 20°C to 60°C
- Temperature stability +/- 1°C
- · Small capacity enables fast current pulsing
- 1 or 3 chuck geometry possible

Test Chamber

The test chamber is the area where the characterization of the DUT is performed.

- Laser safety design (Laser Class 1)
- · Easy to change probe head
- Electronically adjustable force control
- Camera system for automated process control and process observation
- Integration sphere with option for water cooling



Housing & (

- Steel base
- Cover with |
- Control Syst
- 2x 17" TFT-D Keyboard &
- Motion Con
- Linear and
- Pneumatic s

Applications

- Electro-optical characterization of unmounted laser diode bars
- Characterization of VCSEL
- Characterization of bare single chips
- Test of photodiode bars
- Test of chip on submount (COS)
- Full test of high power laser



Measurement Technology

Current driver, integrating sphere, photo diodes, spectrum analysers and test equipment is chosen according to the customer application. The following boundaries can be set:

- Current range: 0 to 5 A Single
- Emitter: 0 to 100 A Full Bar (higher on request)
- Pulse width: 500 ns to 10 ms
- Spectral range: 100 nm out of 350 to 1600 nm

Control

oneumatic door em with PC visplays, Trackball trol System for rotary motion system switchboard panel



Key Features

- LIV, spectral and far & near field tests
- Fully automatic handling of devices
- Easy to change probe head
- Option for component top side and facet inspection
- Flexible integration of external test algorithms and test systems
- Compatible to SQL and other database systems for data traceability

TL2000 Motion System

Features	X, Y, Z Axis	Phi-Z Axis
• Travel	800, 200, 100 mm	270°
• Resolution	100 nm	2 arcsec
 Repeatability 	± 1 μm	8 arcsec

Easy Operation Interface

As a unique feature all ficonTEC machines offer a sophisticated component tracking throughout the entire machine process and across ficonTEC machines.

All machines run the same machine software for easy operation and portability.





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ISO 9001 Certification